

OptiMOS® Power-Transistor

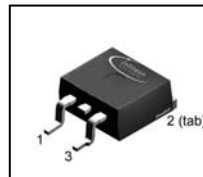
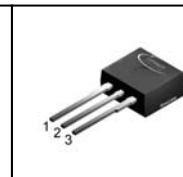
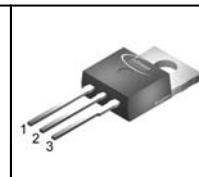


Features

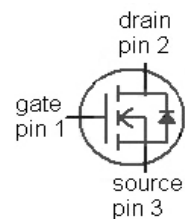
- N-channel - Enhancement mode
- Automotive AEC Q101 qualified
- MSL1 up to 260°C peak reflow
- 175°C operating temperature
- Ultra low Rds(on)
- 100% Avalanche tested
- Green product (RoHS compliant)

Product Summary

| | | |
|--------------------------------|-----|----|
| V_{DS} | 40 | V |
| $R_{DS(on),max}$ (SMD version) | 3.7 | mΩ |
| I_D | 80 | A |

PG-TO263-3-2

PG-TO262-3-1

PG-TO220-3-1


| Type | Package | Marking |
|----------------|--------------|---------|
| IPB80N04S2-H4 | PG-TO263-3-2 | 2N04H4 |
| IPP80N04S2-H4 | PG-TO220-3-1 | 2N04H4 |
| IPI80N04S2-0H4 | PG-TO262-3-1 | 2N04H4 |



Maximum ratings, at $T_J=25\text{ °C}$, unless otherwise specified

| Parameter | Symbol | Conditions | Value | Unit |
|--|-------------------|--|--------------|------|
| Continuous drain current ¹⁾ | I_D | $T_C=25\text{ °C}$, $V_{GS}=10\text{ V}$ | 80 | A |
| | | $T_C=100\text{ °C}$, $V_{GS}=10\text{ V}^{2)}$ | 80 | |
| Pulsed drain current ²⁾ | $I_{D,pulse}$ | $T_C=25\text{ °C}$ | 320 | |
| Avalanche energy, single pulse | E_{AS} | $I_D=80\text{ A}$ | 660 | mJ |
| Gate source voltage | V_{GS} | | ±20 | V |
| Power dissipation | P_{tot} | $T_C=25\text{ °C}$ | 300 | W |
| Operating and storage temperature | T_J , T_{stg} | | -55 ... +175 | °C |
| IEC climatic category; DIN IEC 68-1 | | | 55/175/56 | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Thermal characteristics²⁾

| | | | | | | |
|--|------------|--|---|---|-----|-----|
| Thermal resistance, junction - case | R_{thJC} | | - | - | 0.5 | K/W |
| Thermal resistance, junction - ambient, leaded | R_{thJA} | | - | - | 62 | |
| SMD version, device on PCB | R_{thJA} | minimal footprint | - | - | 62 | |
| | | 6 cm ² cooling area ³⁾ | - | - | 40 | |

Electrical characteristics, at $T_j=25\text{ °C}$, unless otherwise specified

Static characteristics

| | | | | | | |
|----------------------------------|---------------|---|-----|------|-----|---------------|
| Drain-source breakdown voltage | $V_{(BR)DSS}$ | $V_{GS}=0\text{ V}$, $I_D=1\text{ mA}$ | 40 | - | - | V |
| Gate threshold voltage | $V_{GS(th)}$ | $V_{DS}=V_{GS}$, $I_D=250\text{ }\mu\text{A}$ | 2.1 | 3.0 | 4.0 | |
| Zero gate voltage drain current | I_{DSS} | $V_{DS}=40\text{ V}$, $V_{GS}=0\text{ V}$, $T_j=25\text{ °C}$ | - | 0.01 | 1 | μA |
| | | $V_{DS}=40\text{ V}$, $V_{GS}=0\text{ V}$, $T_j=125\text{ °C}^{2)}$ | - | 1 | 100 | |
| Gate-source leakage current | I_{GSS} | $V_{GS}=20\text{ V}$, $V_{DS}=0\text{ V}$ | - | 1 | 100 | nA |
| Drain-source on-state resistance | $R_{DS(on)}$ | $V_{GS}=10\text{ V}$, $I_D=80\text{ A}$ | - | 3.5 | 4.0 | m Ω |
| | | $V_{GS}=10\text{ V}$, $I_D=80\text{ A}$, SMD version | - | 3.2 | 3.7 | |

| Parameter | Symbol | Conditions | Values | | | Unit |
|-----------|--------|------------|--------|------|------|------|
| | | | min. | typ. | max. | |

Dynamic characteristics²⁾

| | | | | | | |
|------------------------------|--------------|---|---|------|---|----|
| Input capacitance | C_{iss} | $V_{GS}=0\text{ V}, V_{DS}=25\text{ V},$ $f=1\text{ MHz}$ | - | 4400 | - | pF |
| Output capacitance | C_{oss} | | - | 1800 | - | |
| Reverse transfer capacitance | C_{rss} | | - | 480 | - | |
| Turn-on delay time | $t_{d(on)}$ | $V_{DD}=20\text{ V}, V_{GS}=10\text{ V},$ $I_D=80\text{ A}, R_G=1.3\ \Omega$ | - | 23 | - | ns |
| Rise time | t_r | | - | 63 | - | |
| Turn-off delay time | $t_{d(off)}$ | | - | 46 | - | |
| Fall time | t_f | | - | 22 | - | |

Gate Charge Characteristics²⁾

| | | | | | | |
|-----------------------|---------------|--|---|-----|-----|----|
| Gate to source charge | Q_{gs} | $V_{DD}=32\text{ V}, I_D=80\text{ A},$ $V_{GS}=0\text{ to }10\text{ V}$ | - | 21 | 29 | nC |
| Gate to drain charge | Q_{gd} | | - | 38 | 70 | |
| Gate charge total | Q_g | | - | 103 | 148 | |
| Gate plateau voltage | $V_{plateau}$ | | - | 4.9 | - | V |

Reverse Diode

| | | | | | | |
|--|---------------|---|---|-----|-----|----|
| Diode continuous forward current ²⁾ | I_S | $T_C=25\text{ °C}$ | - | - | 80 | A |
| Diode pulse current ²⁾ | $I_{S,pulse}$ | | - | - | 320 | |
| Diode forward voltage | V_{SD} | $V_{GS}=0\text{ V}, I_F=80\text{ A},$ $T_j=25\text{ °C}$ | - | 0.9 | 1.3 | V |
| Reverse recovery time ²⁾ | t_{rr} | $V_R=20\text{ V}, I_F=I_S,$ $di_F/dt=100\text{ A}/\mu\text{s}$ | - | 195 | - | ns |
| Reverse recovery charge ²⁾ | Q_{rr} | $V_R=20\text{ V}, I_F=I_S,$ $di_F/dt=100\text{ A}/\mu\text{s}$ | - | 370 | - | nC |

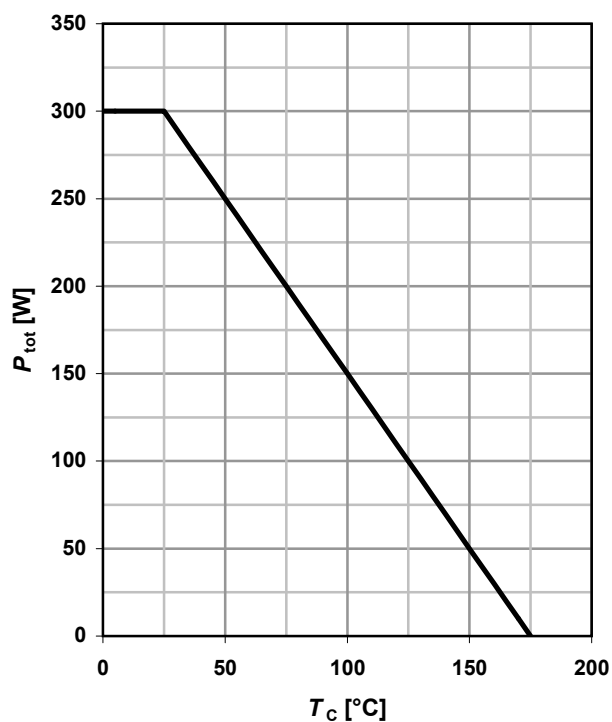
¹⁾ Current is limited by bondwire; with an $R_{thJC} = 0.5\text{K/W}$ the chip is able to carry 200A at 25°C. For detailed information see Application Note ANPS071E at www.infineon.com/optimos

²⁾ Defined by design. Not subject to production test.

³⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 µm thick) copper area for drain connection. PCB is vertical in still air.

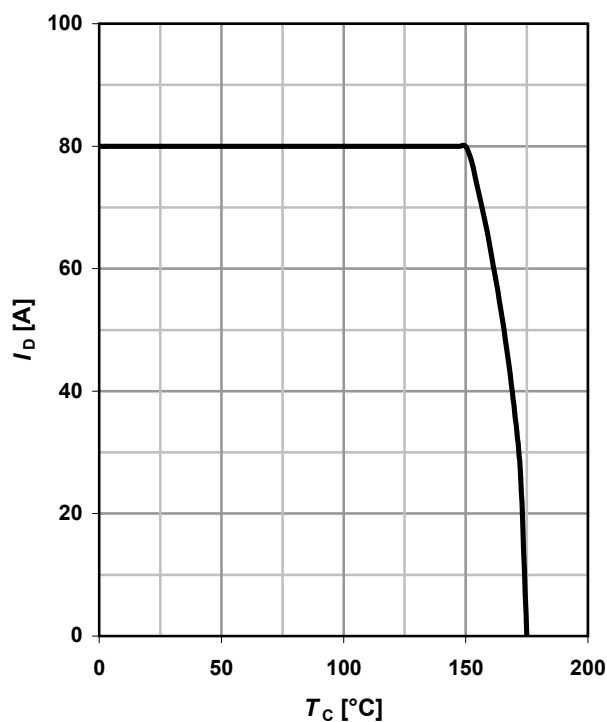
1 Power dissipation

$$P_{\text{tot}} = f(T_C); V_{\text{GS}} \geq 6 \text{ V}$$



2 Drain current

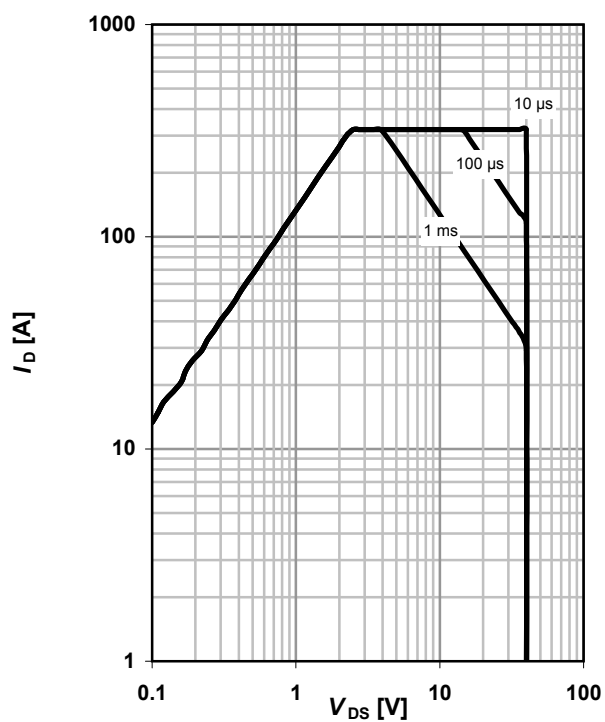
$$I_D = f(T_C); V_{\text{GS}} \geq 10 \text{ V}$$



3 Safe operating area

$$I_D = f(V_{\text{DS}}); T_C = 25 \text{ °C}; D = 0$$

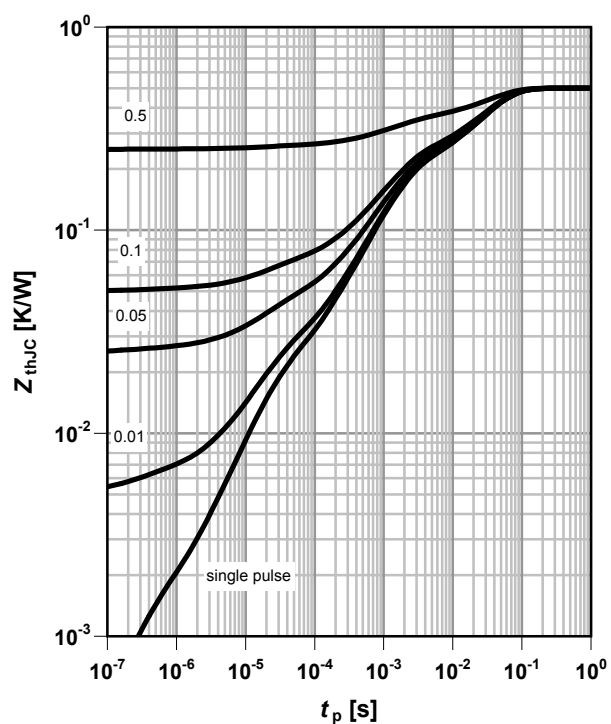
parameter: t_p



4 Max. transient thermal impedance

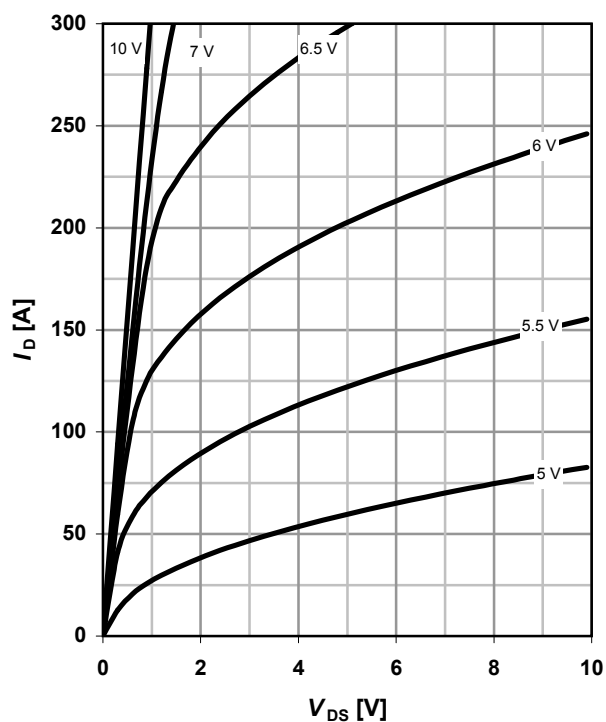
$$Z_{\text{thJC}} = f(t_p)$$

parameter: $D = t_p/T$



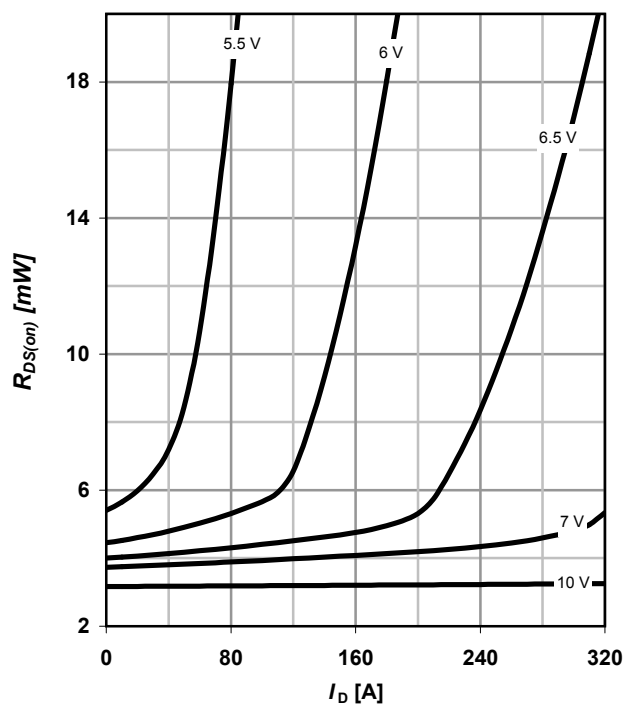
5 Typ. output characteristics

 $I_D = f(V_{DS}); T_j = 25^\circ\text{C}$

parameter: V_{GS}


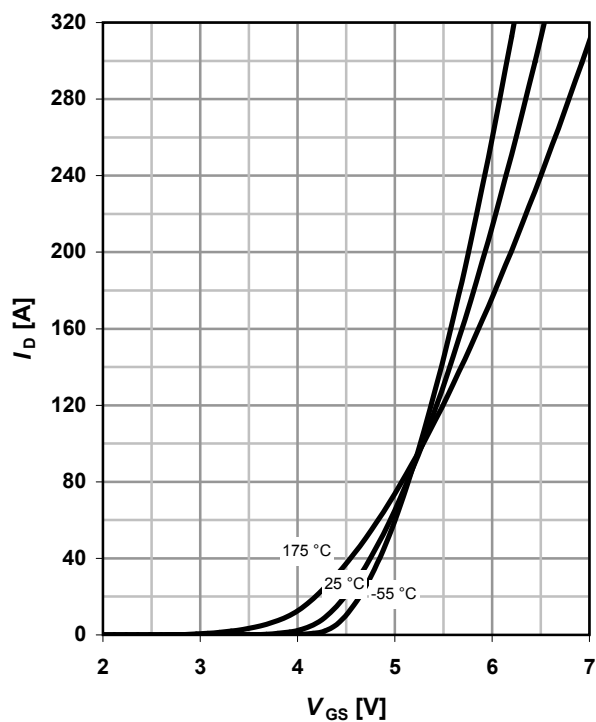
6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25^\circ\text{C}$

parameter: V_{GS}


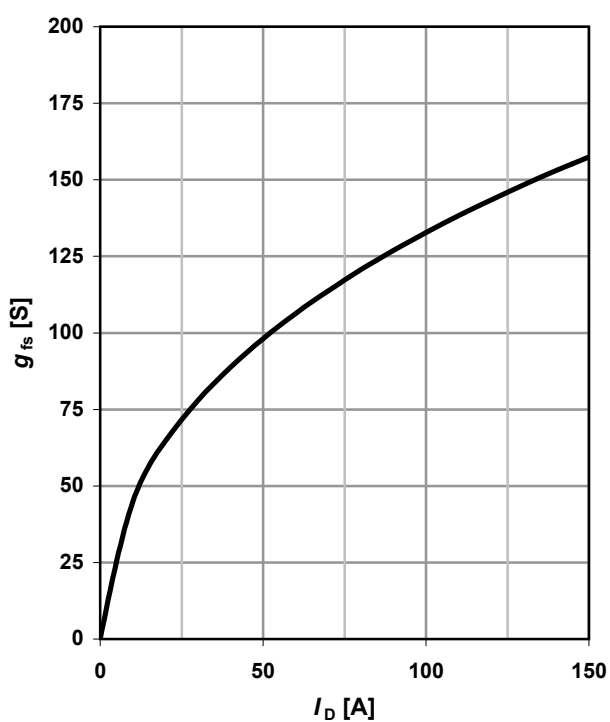
7 Typ. transfer characteristics

 $I_D = f(V_{GS}); V_{DS} = 6\text{V}$

parameter: T_j


8 Typ. Forward transconductance

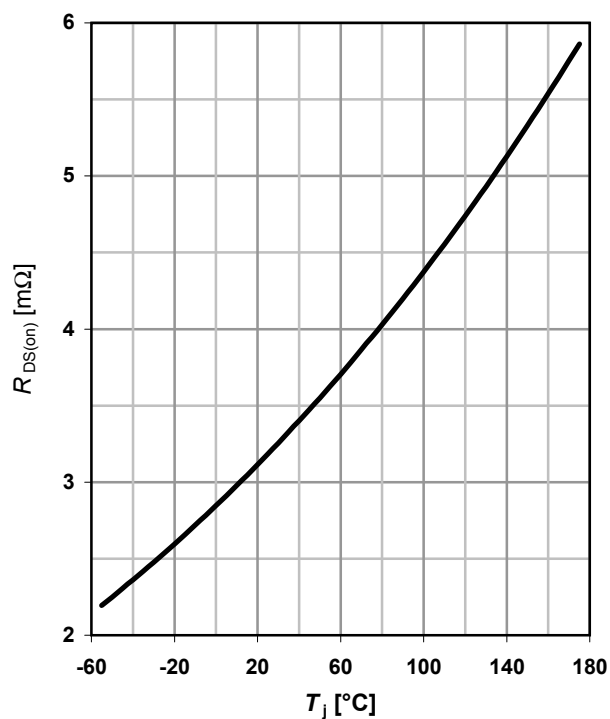
 $g_{fs} = f(I_D); T_j = 25^\circ\text{C}$

parameter: g_{fs}


9 Typ. Drain-source on-state resistance

$$R_{DS(on)} = f(T_j)$$

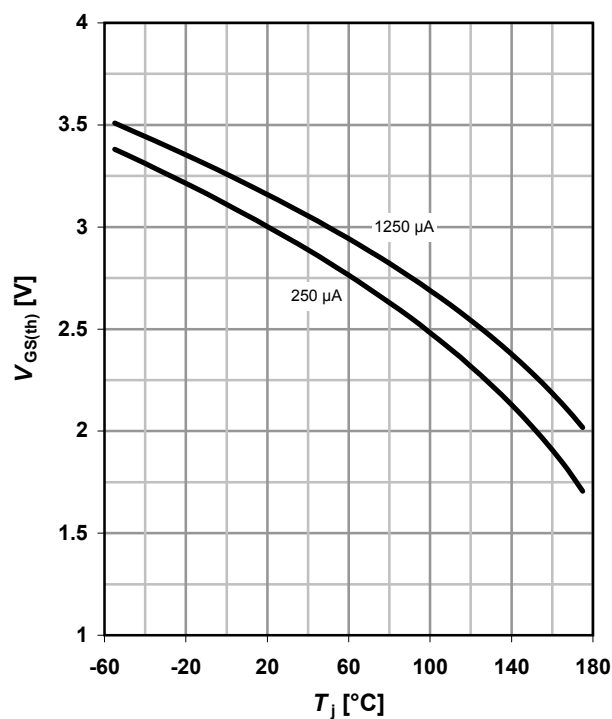
parameter: $I_D = 80 \text{ A}$; $V_{GS} = 10 \text{ V}$



10 Typ. gate threshold voltage

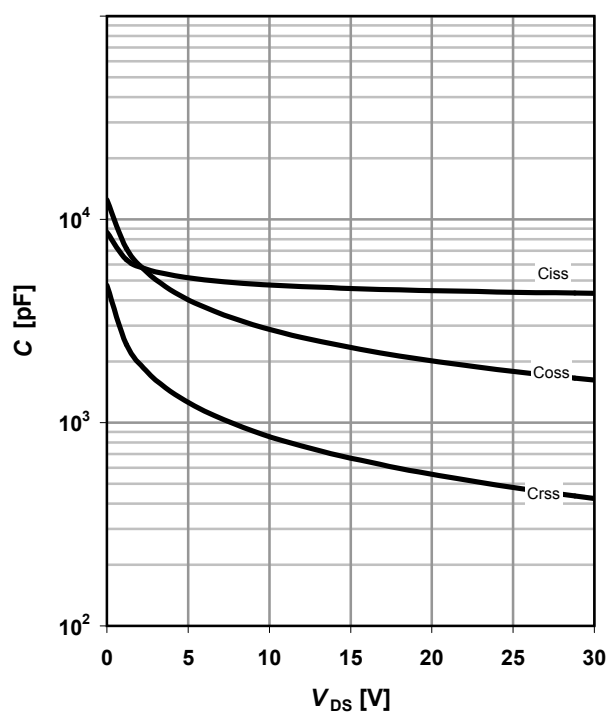
$$V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$$

parameter: I_D



11 Typ. capacitances

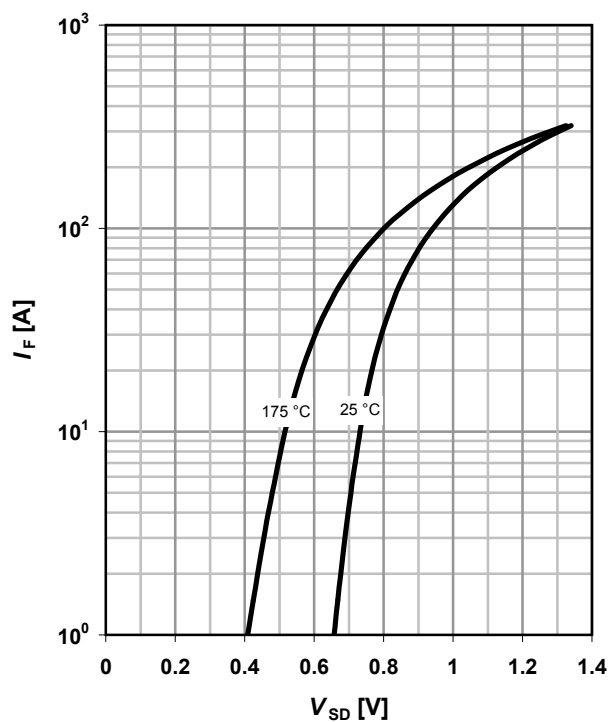
$$C = f(V_{DS}); V_{GS} = 0 \text{ V}; f = 1 \text{ MHz}$$



12 Typical forward diode characteristics

$$I_F = f(V_{SD})$$

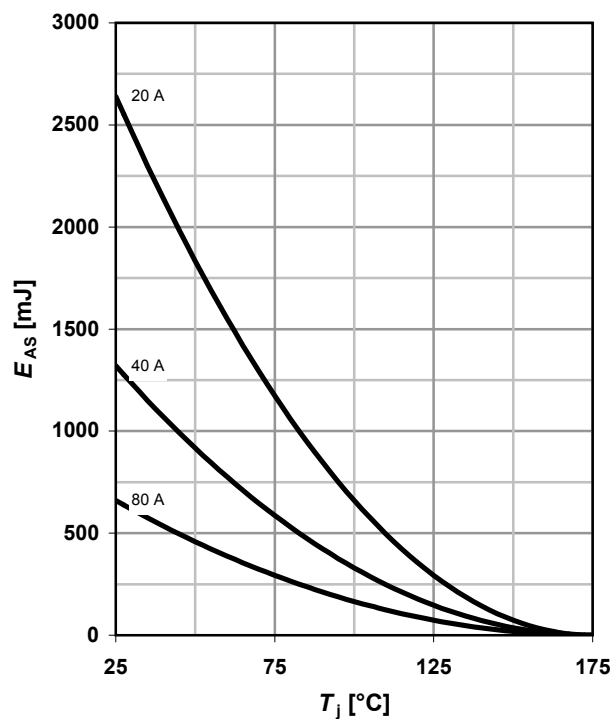
parameter: T_j



13 Avalanche energy

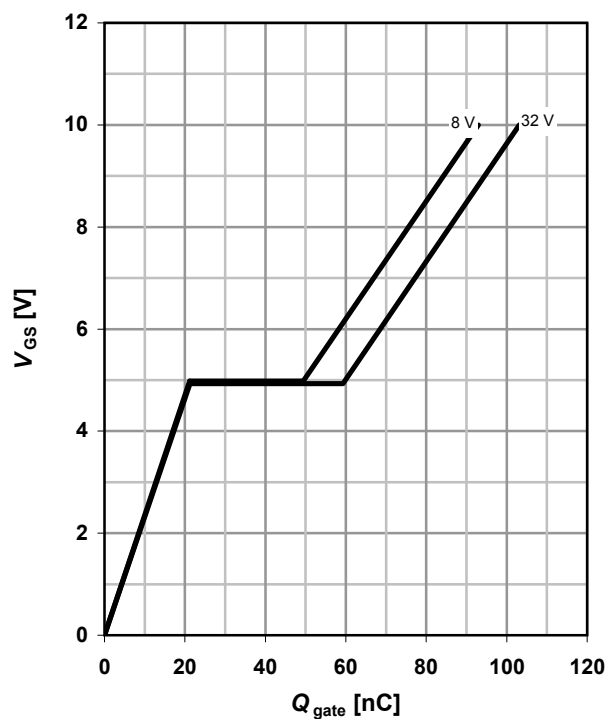
$$E_{AS} = f(T_j)$$

parameter: I_D



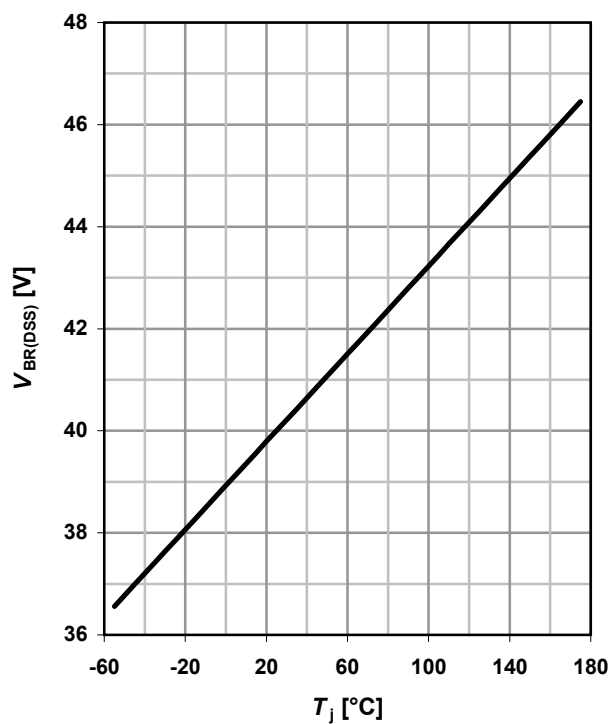
14 Typ. gate charge

$$V_{GS} = f(Q_{gate}); I_D = 80 \text{ A pulsed}$$

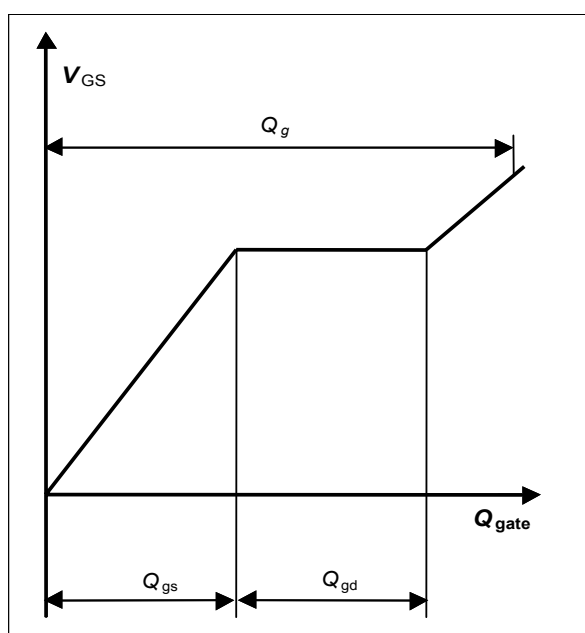


15 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = 1 \text{ mA}$$



16 Gate charge waveforms



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Revision History

| Version | Date | Changes |
|--------------|------------|---|
| Revision 1.1 | 22.02.2008 | Update of side 1 and 10 according to new template |
| Revision 1.1 | 22.02.2008 | Update of SOA diagram, labelling |